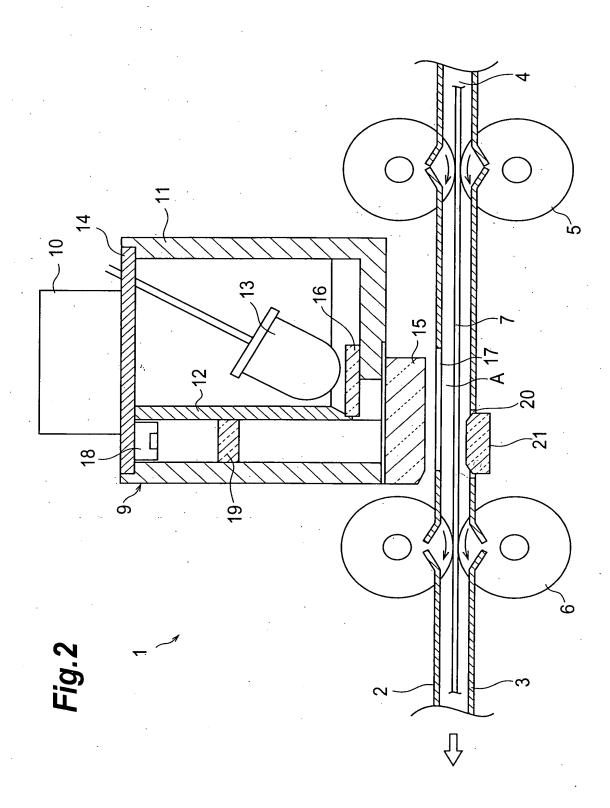
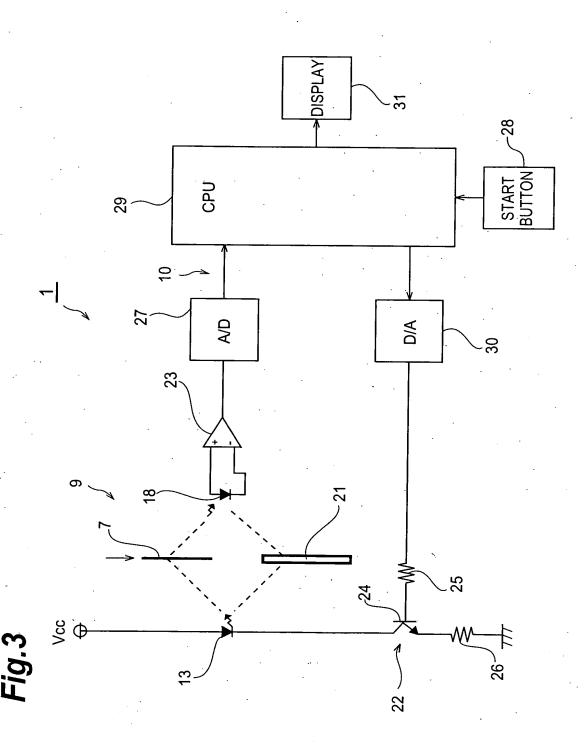


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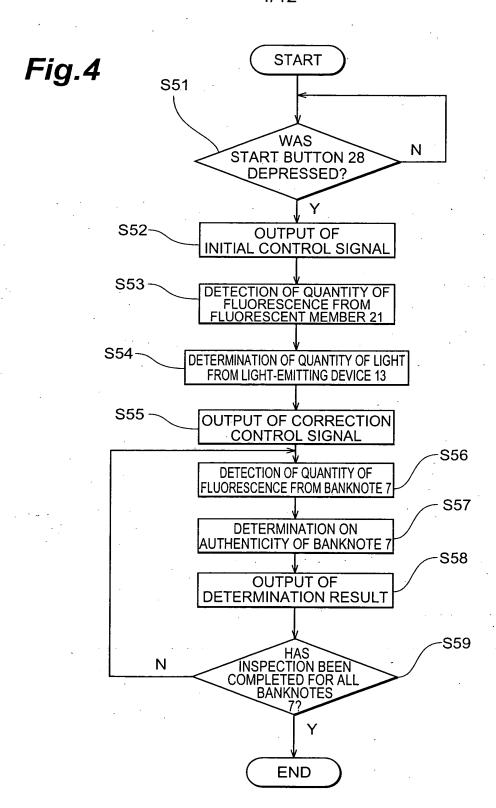
Title: INSPECTION APPARATUS AND INSPECTION METHOD

Inventors: Hideaki KAMIJO Atty Docket No.: 402985

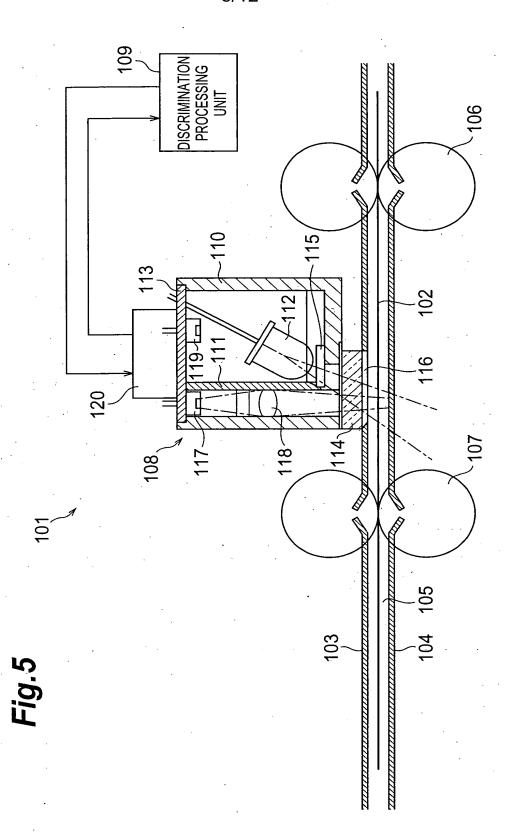
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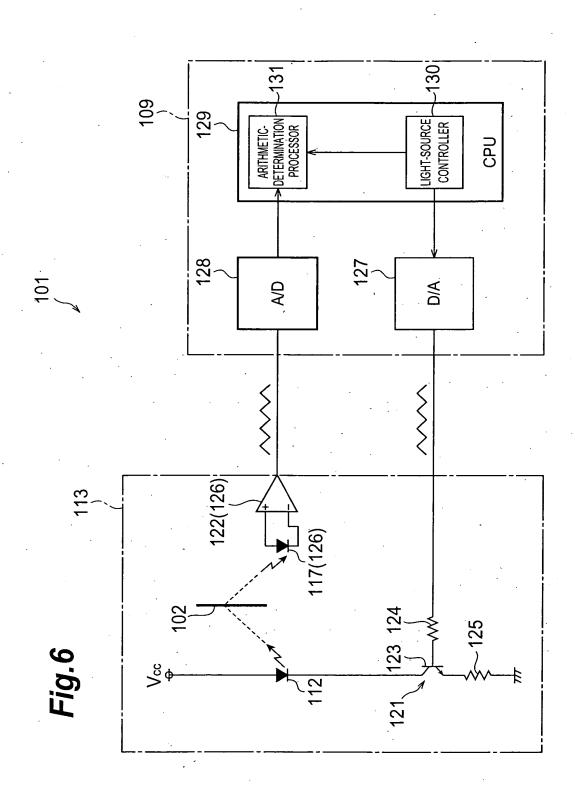
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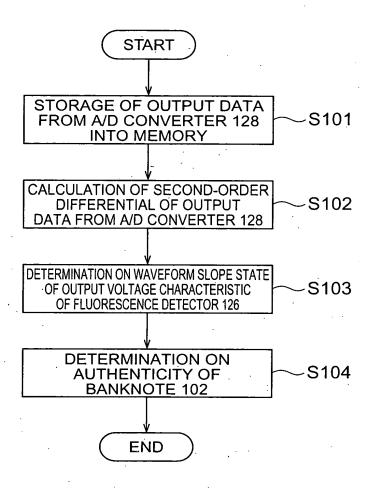
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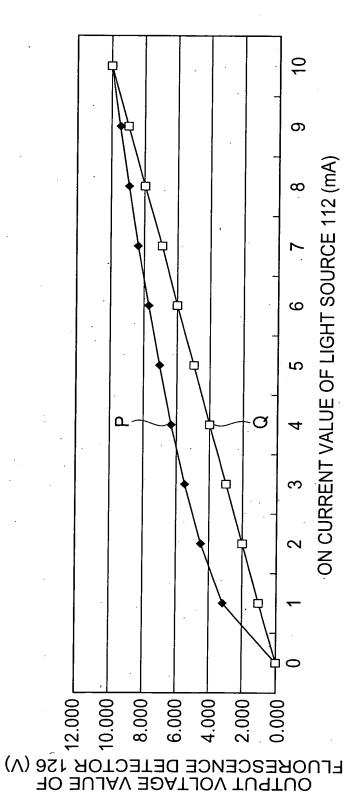
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Fig.7







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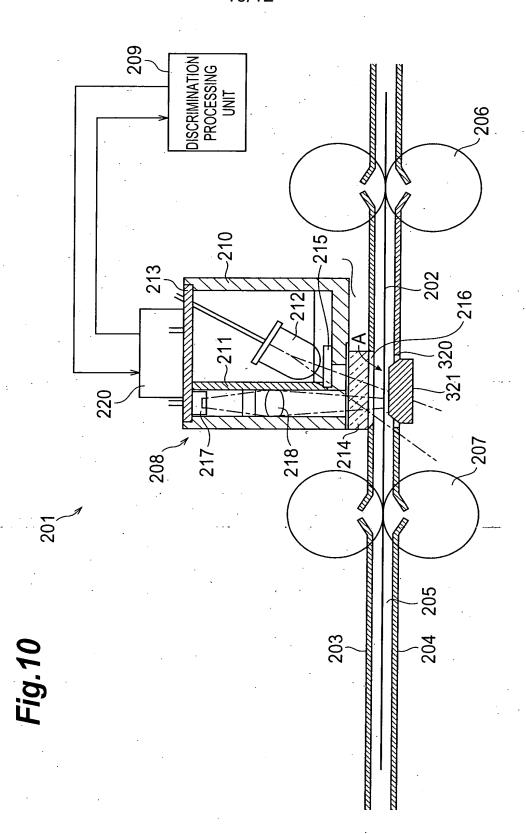
# Fig.9A

LIGHT-SOURCE ON CURRENT (mA)	OUTPUT VOLTAGE (V)	FIRST-ORDER DIFFERENTIAL	SECOND-ORDER DIFFERENTIAL
0	0.000		
1	3.163	3.163	
2	4.473	1.310	-1.853
3	5.478	1.005	-0.305
4	6.325	0.847	-0.158
5	7.072	0.747	-0.101
6	7.747	0.675	-0.072
7	8.367	0.621	-0.054
8	8.945	0.578	-0.043
9	9.488	0.543	-0.035
10	10.001	0.513	-0.029
DETERMINATION (SLOPE OF WAVEFORM)			— (MINUS)

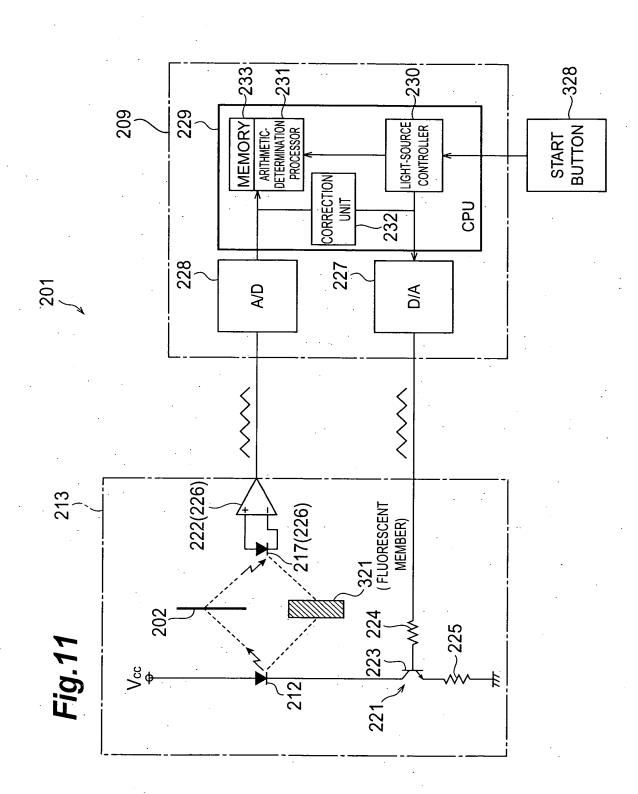
## Fig.9B

LIGHT-SOURCE ON CURRENT (mA)	OUTPUT VOLTAGE (V)	FIRST-ORDER DIFFERENTIAL	SECOND-ORDËR DIFFERENTIAL
0	0.000		
1	1.000	1.000	
2	2.000	1.000	0.000
3	3.000	1.000	0.000
4	4.000	1.000	0.000
5	5.000	1.000	0.000
6	6.000	1.000	0.000
7	7.000	1.000	0.000
8	8.000	1.000	0.000
9	9.000	1.000	0.000
10	10.000	1.000	0.000
DETERMINATION (SLOPE OF WAVEFORM)			0 (ZERO)

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